

Special Issue

Super-resolution Networks in Machine Learning

Message from the Guest Editor

Super resolution (SR) aims to increase the size of a given input low-resolution (LR) image by recovering high-frequency details. SR has gathered a lot of interest as high resolution displays are becoming increasingly common in many smartphones, TVs, and monitors, and thus have become an active research topic. In particular, with the aid of recent advances in deep learning, many state-of-the-art SR methods have produced promising results, and we are interested in articles that explore these learning-based SR approaches. Potential topics include, but are not limited to, the following:

- Image/video upsampling and super-resolution algorithms;
- Real-time image super resolution;
- Large-factor image super resolution;
- Real-image super resolution;
- Studies and applications of the above.

Keywords

- computation imaging
- super-resolution
- enhancement
- upsampling
- machine learning
- deep learning
- CNN

Guest Editor

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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

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